



IN THE UNITED STATES DESIGNATED OFFICE  
OF THE UNITED STATES PATENT AND TRADEMARK OFFICE  
UNDER THE PATENT COOPERATION TREATY-CHAPTER II

**INFORMATION DISCLOSURE STATEMENT**

5 APPLICANT: Reiner Franz Schulz CONFIRMATION NO. 7105

SERIAL NO.: 10/564,078 GROUP ART UNIT: 2882

FILED: January 9, 2006

TITLE: METHOD FOR THE PRODUCTION OF A CORRECTED  
X-RAY IMAGE DATA SET

10 **MAIL STOP AMENDMENT**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, Virginia 22313-1450

Sir:

15 In accordance with the provisions of 37 C.F.R. § 1.56, Applicant  
requests that citation and examination of the following documents be made  
during the course of examination of the above-referenced application.

AA United States Patent No. 5,832,055  
AL DE 197 19 954 A1  
20 AT "The Physics of Computed Radiography," Rowlands, Phys.  
Med. Biol., Vol. 47 (2002) R123-R166  
AU "Digitale Detektorsysteme für die Projektionsradiographie,"  
RöFo Fortschr. Röntgenstr., Vol. 173 (2001), pgs 1137-1146  
AV "Langzeitergebnisse der Konstanzer Prüfung an einem  
25 Spechierfoliensystem," Krause et al., Jahrestagung Med.  
Physik Gmunden (2002)

**EXPLANATION OF RELEVANCE**

Reference AU was identified and discussed at pages 1 and 5 \_\_\_\_ of  
the substitute specification. A complete English translation of that reference is  
30 not readily available to the Applicant, however, in addition to the statements in

the specification concerning that reference, Reference AU contains an English language Abstract.

References AL, AT and AV were cited in the International Search Report rendered during earlier PCT examination of the present application.

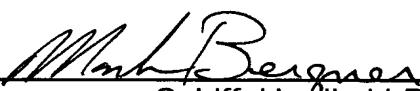
5       Reference AA is a further reference known to the Applicant that discloses a method for correcting defects in a radiation image by generating a calibration matrix that contains respective correction values for each pixel. The values in the calibration matrix represent, for each pixel, the deviation of the value that is effectively obtained for the pixel when the recording medium is  
10 subjected to a flat field exposure, and the value that would be expected in the pixel.

Copies of References AL, AT, AU and AV are submitted herewith, together with Form 1449 on which all of the references are listed.

As of the date of mailing of this Information Disclosure Statement, a first  
15 Office Action on the merits has not been received in connection with this application, and therefore, this Information Disclosure Statement is in compliance with 37 C.F.R. §1.97(b)(3), and no fee is necessary.

All claims of the application are submitted to be patentable over the teachings of the above references, taken singly or in combination. Early  
20 consideration of the application is therefore respectfully requested.

Submitted by,

  
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**CERTIFICATE OF MAILING**

JUN 21 2006

I hereby certify that this correspondence is being deposited with the United States Postal Service as First Class mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, Virginia 22313-1450 on June 14, 2006.

  
MARK BERGNER

Form PTO-1449



**INFORMATION DISCLOSURE CITATION  
IN AN APPLICATION**  
(use several sheets if necessary)

Docket No.  
P05,0445Serial No.  
10/564,078Applicant  
Reiner Franz SchulzFiling Date  
January 9, 2006Group Art Unit  
2882

**U.S. PATENT DOCUMENTS**

Examiner's Initials		Document Number	Date	Name	Class	Subclass	Filing Date If appropriate
	AA	5,832,055	11/3/98	Dewaele			
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

**FOREIGN PATENT DOCUMENTS**

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AL	DE 197 19 954 A1	11/19/98	Germany				
	AM							
	AN							
	AO							
	AP							
	AQ							
	AR							
	AS							

**OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)**

	AT	"The Physics of Computed Radiography," Rowlands, Phys. Med. Biol., Vol. 47 (2002) R123-R166
	AU	"Digitale Detektorsysteme für die Projektionsradiographie," RöFo Fortschr. Röntgenstr., Vol. 173 (2001), pgs 1137-1146
	AV	"Langzeitergebnisse der Konstanzprüfung an einem Spechierfoliensystem," Krause et al., Jahrestagung Med. Physik Gmunden (2002)
	AW	

Examiner	Date Considered
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\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.